Systematic Design of Analog Circuits Using Pre-Computed Lookup Tables

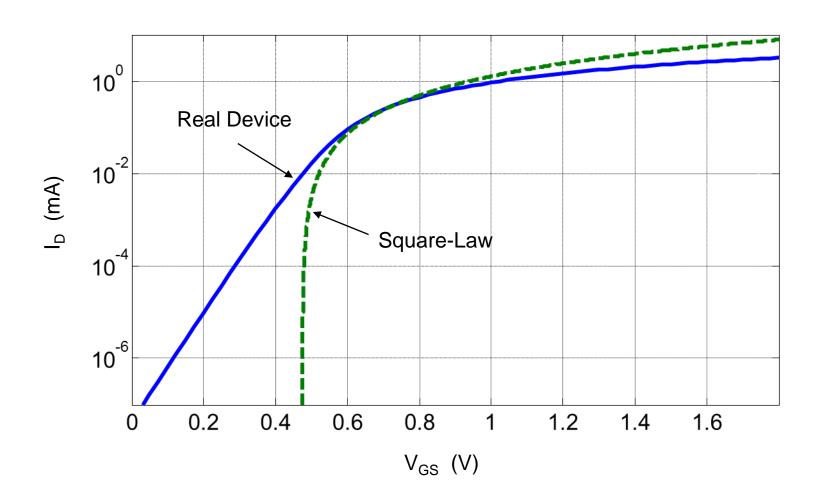


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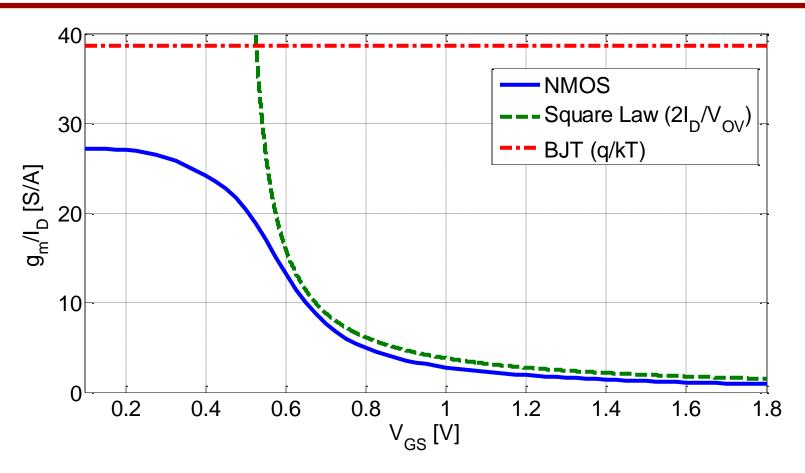
Outline

- Motivation
- Examples
 - Simple differential pair
 - Noise-limited gain stages
 - Distortion-limited gain stages
 - Design with process corners

Motivation: Complex MOS I-V

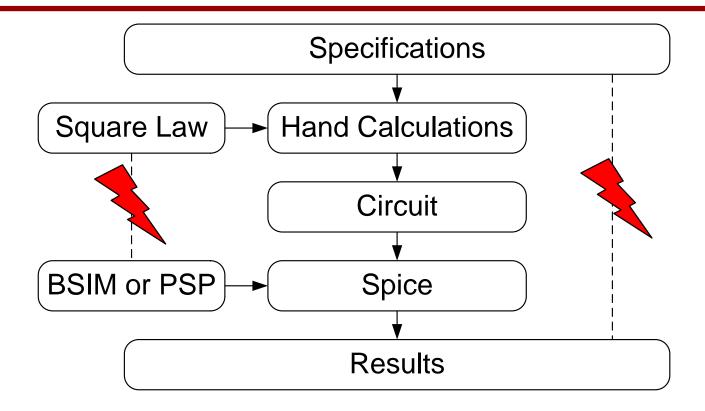


g_m/I_D



 The square law fails miserably at predicting g_m/I_D in moderate and weak inversion

The Problem



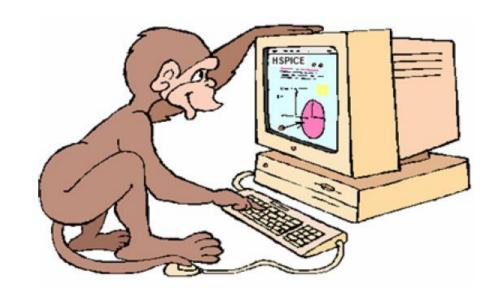
 Since there is a disconnect between actual transistor behavior and the simple square law model, any square-law driven design optimization will be far off from Spice results

To Be Avoided: Spice Monkeying

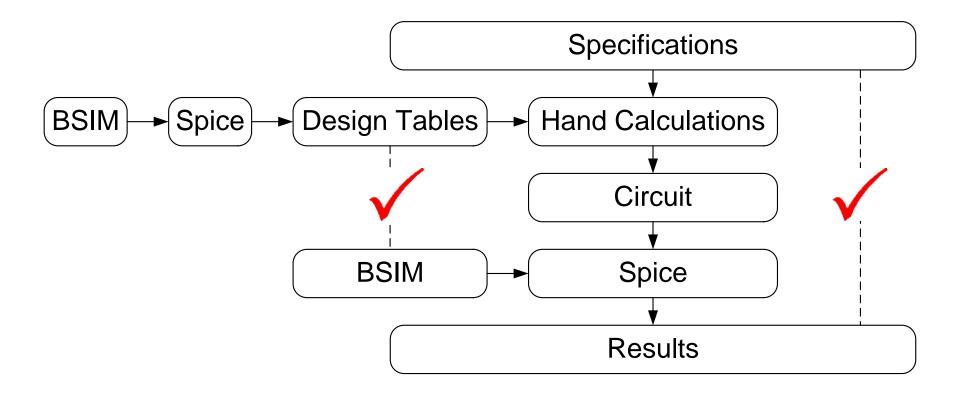
 One way to solve this problem is to "poke around" in Spice and play this out like a video game...

Issues

- Learn nothing about fundamental tradeoffs and optimality
- Will not detect simulation or modeling errors



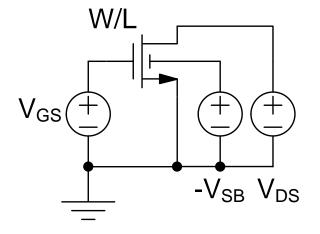
The Solution



Use pre-computed spice data in hand calculations

Starting Point: Technology Characterization via DC Sweep

```
* /usr/class/ee214b/hspice/techchar.sp
.inc '/usr/class/ee214b/hspice/ee214 hspice.sp'
.inc 'techchar params.sp'
.param ds = 0.9
.param qs = 0.9
                       dc 'ds'
vdsn
         vdn 0
vqsn
        vgn 0
                     dc 'gs'
vbsn
        vbn 0
                      dc '-subvol'
         vdn vgn 0 vbn nmos214 L='length' W='width'
mn
.options dccap post brief accurate nomod
.dc qs 0 'qsmax' 'qsstep' ds 0 'dsmax' 'dsstep'
.probe n id
             = par('i(mn)')
.probe n vt = par('vth(mn)')
.probe n gm = par('gmo(mn)')
.probe n gmb = par('gmbso(mn)')
.probe n gds = par('gdso(mn)')
.probe n cgg = par('cggbo(mn)')
.probe n cgs = par('-cgsbo(mn)')
.probe n cgd = par('-cgdbo(mn)')
.probe n cqb = par('cbqbo(mn)')
.probe n cdd = par('cddbo(mn)')
.probe n css
              = par('-cbsbo(mn)-cgsbo(mn)')
```



Store Data in a Matlab Structure

```
% data stored in /usr/class/ee214b/matlab
>> load 180nch.mat;
>> nch
nch =
     ID: [4-D double]
    VT: [4-D double]
     GM: [4-D double]
    GMB: [4-D double]
    GDS: [4-D double]
    CGG: [4-D double]
    CGS: [4-D double]
    CGD: [4-D double]
    CGB: [4-D double]
    CDD: [4-D double]
    CSS: [4-D double]
    VGS: [73x1 double]
    VDS: [73x1 double]
    VSB: [11x1 double]
      L: [22x1 double]
      W: 5
>> size(nch.ID)
ans =
    22
          73
                73
                       11
```

Four-dimensional arrays

$$I_D(L, V_{GS}, V_{DS}, V_{SB})$$
 $V_t(L, V_{GS}, V_{DS}, V_{SB})$
 $g_m(L, V_{GS}, V_{DS}, V_{SB})$
...

Lookup Function (For Convenience)

```
>> lookup(nch, 'ID', 'VGS', 0.5, 'VDS', 0.5)
ans = 8.4181e-006
>> help lookup
  The function "lookup" extracts a desired subset from the 4-dimensional
  simulation data. The function interpolates when the requested points lie off
  the simulation grid.
    There are three basic usage modes:
    (1) Simple lookup of parameters at given (L, VGS, VDS, VSB)
    (2) Lookup of arbitrary ratios of parameters, e.g. GM ID, GM CGG at given
        (L, VGS, VDS, VSB)
    (3) Cross-lookup of one ratio against another, e.g. GM CGG for some GM ID
    In usage scenarios (1) and (2) the input parameters (L, VGS, VDS, VSB) can be
    listed in any order and default to the following values when not specified:
   L = min(data.L); (minimum length used in simulation)
   VGS = data.VGS; (VGS vector used during simulation)
   VDS = max(data.VDS)/2; (VDD/2)
   VSB = 0;
```

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Download

http://web.stanford.edu/~murmann/gmid

Key Question

- How can we use all this data for <u>systematic</u> design?
- Many options exist
 - And you can invent your own, if you like
- Method that I promote
 - Look at the transistor in terms of width-independent figures of merit that are intimately linked to design specification
 - Rather than some physical modeling parameters that do not directly relate to circuit specs)
 - Think about the design tradeoffs in terms of the MOSFET's inversion level, using g_m/I_D as a proxy

Figures of Merit for Design

- Transconductance efficiency
 - Want large g_m, for as little current as possible

$\frac{g_{m}}{I_{D}}$

$$=\frac{2}{V_{OV}}$$

- Transit frequency
 - Want large g_m , without large C_{gg}

$$\frac{g_{m}}{C_{gg}}$$

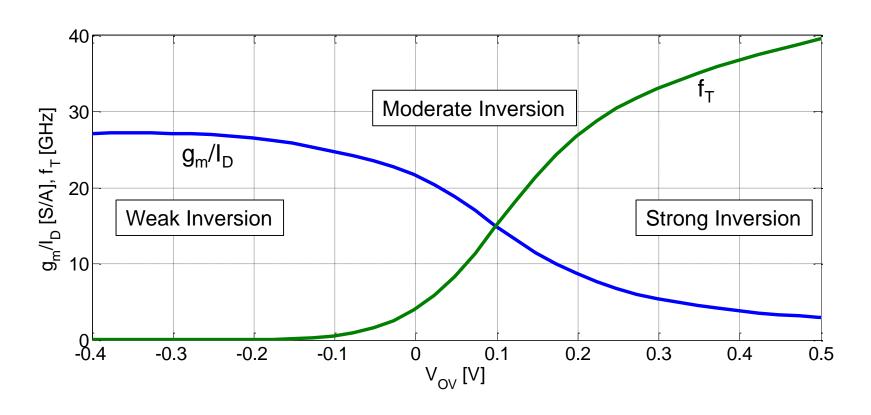
$$\cong \frac{3}{2} \frac{\mu V_{OV}}{L^2}$$

- Intrinsic gain
 - Want large g_m, but no g_o

$$\frac{g_m}{g_o}$$

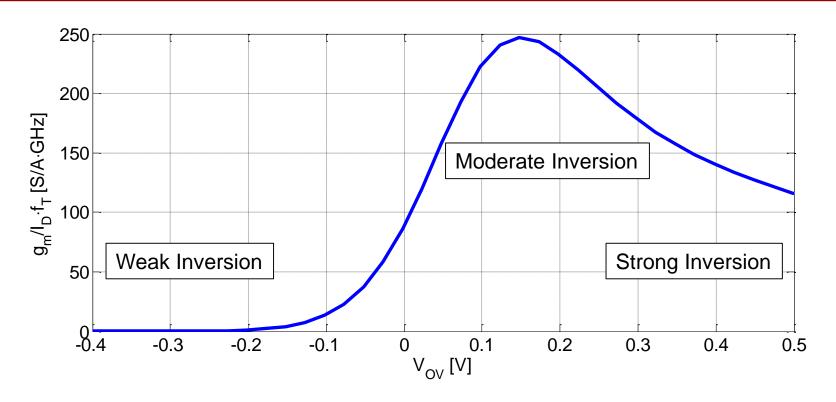
$$\cong \frac{2}{\lambda V_{OV}}$$

Design Tradeoff: g_m/I_D and f_T



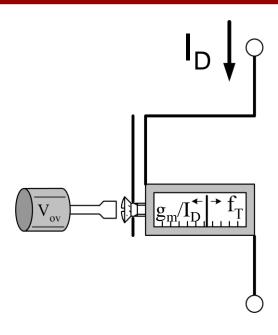
- Weak inversion: Large g_m/I_D (>20 S/A), but small f_T
- Strong inversion: Small g_m/I_D (<10 S/A), but large f_T

Product of g_m/I_D and f_T



- Interestingly, the product of g_m/I_D and f_T peaks in moderate inversion
- Operating the transistor in moderate inversion is optimal when we value speed and power efficiency equally (not always the case)

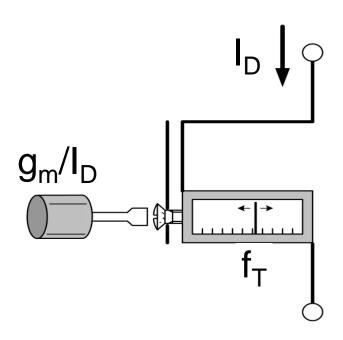
Design in a Nutshell

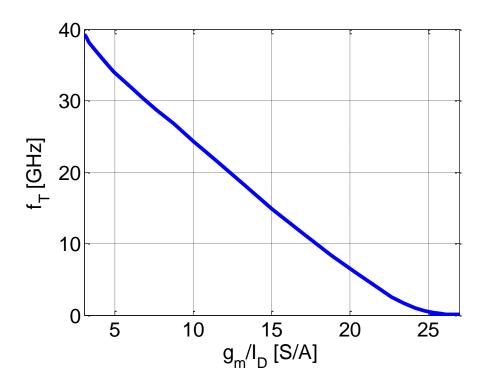


- Choose the inversion level according to the proper tradeoff between speed (f_T) and efficiency (g_m/I_D) for the given circuit
- The inversion level is fully determined by the gate overdrive V_{OV}
 - But, V_{OV} is not a very interesting parameter outside the square law framework; not much can be computed from V_{OV}

Eliminating V_{ov}

- The inversion level is also fully defined once we pick g_m/I_D, so there is no need to know V_{OV}
 - Even V_{Dsat} can be estimated using 2 / (g_m/I_D)



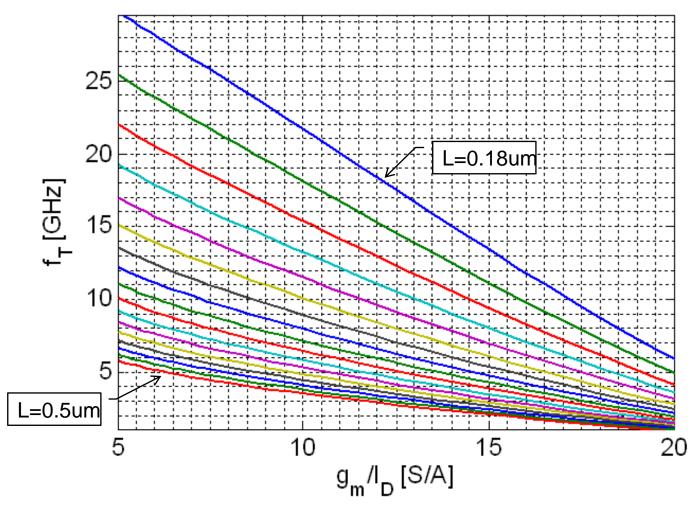


g_m/I_D-centric Technology Characterization

- Plot the following parameters for a reasonable range of g_m/I_D and channel lengths
 - Transit frequency (f_T)
 - Intrinsic gain (g_m/g_o)
- Can also plot relative estimates of extrinsic capacitances
 - C_{gd}/C_{gg} and C_{dd}/C_{gg}
- Note that all of these parameters are (to first order) independent of device width
- In order to compute device widths, we need one more plot that links g_m/I_D and current density I_D/W

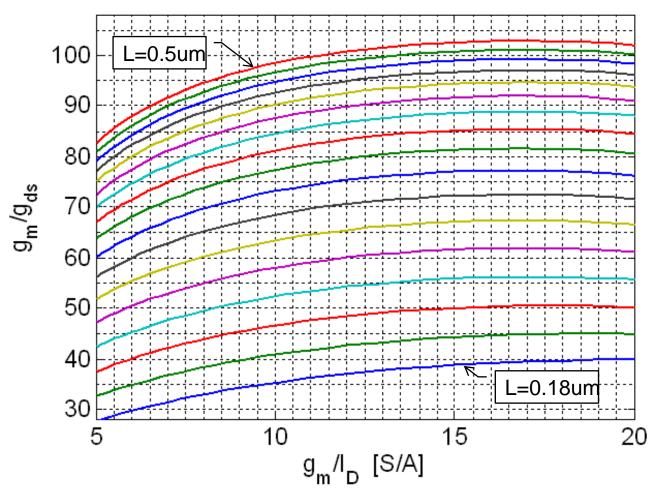
Transit Frequency Chart

NMOS, 0.18...0.5um (step=20nm), V_{DS}=0.9V



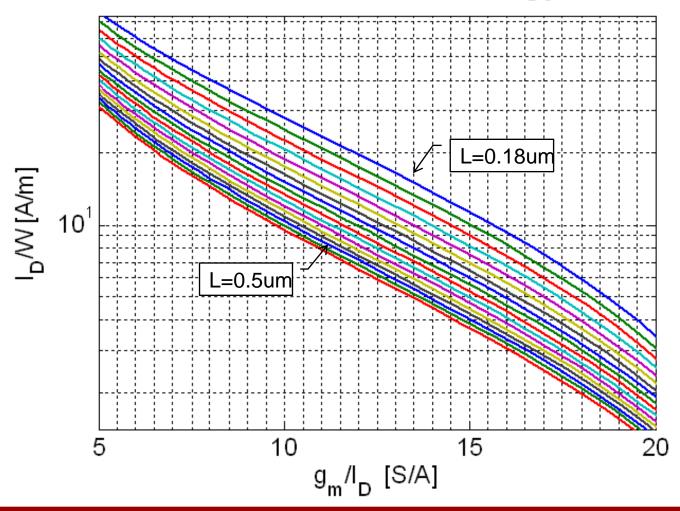
Intrinsic Gain Chart

NMOS, 0.18...0.5um (step=20nm), V_{DS} =0.9V

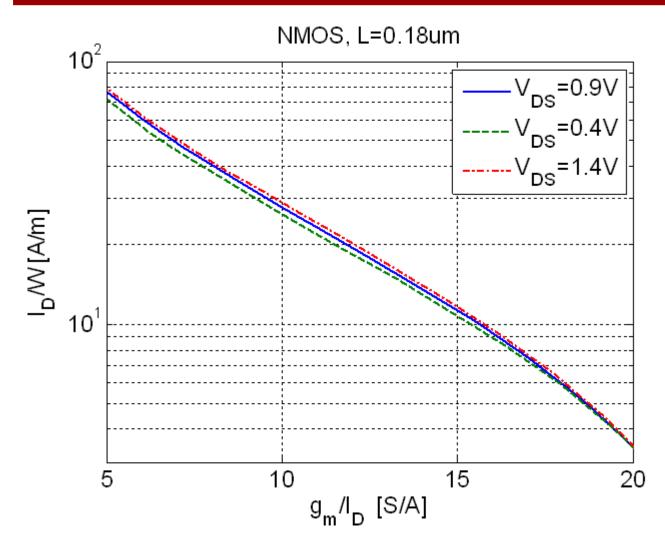


Current Density Chart

NMOS, 0.18...0.5um (step=20nm), V_{DS} =0.9V



V_{DS} Dependence



- V_{DS} dependence is relatively weak
- Typically OK to work with data generated for V_{DD}/2
- But, no problem to use the actual V_{DS} (or a good estimate of it) in the lookup command

Generic Design Flow

- 1) Determine g_m (from design objectives)
- 2) Pick L
 - Short channel → high f_T (high speed)
 - Long channel → high intrinsic gain
- 3) Pick g_m/I_D (or f_T)
 - Large $g_m/I_D \rightarrow low power$, large signal swing (low V_{Dsat})
 - Small $g_m/I_D \rightarrow high f_T (high speed)$
- 4) Determine I_D (from g_m and g_m/I_D)
- 5) Determine W (from I_D/W)

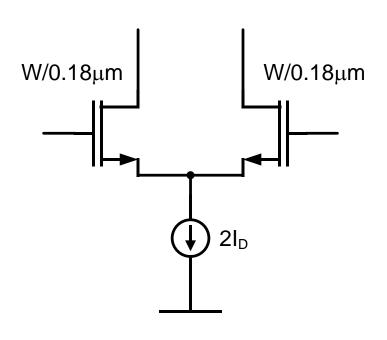
Many other possibilities exist (depending on circuit specifics, design constraints and objectives)

Outline

- Motivation
- Examples
 - Basic differential pair
 - Noise-limited gain stages
 - Distortion-limited gain stages
 - Design with process corners

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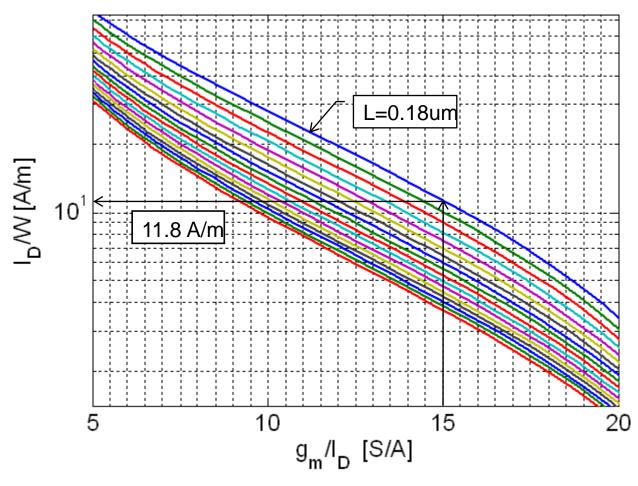
Basic Sizing Example



- Determine the width of the differential pair transistors such that g_m=10mS
- Consider various levels of inversion (weak, moderate, strong)
- For each case, compute the required I_D, W and C_{gg} (total gate capacitance)

Current Density Lookup

NMOS, 0.18...0.5um (step=20nm), V_{DS}=0.9V

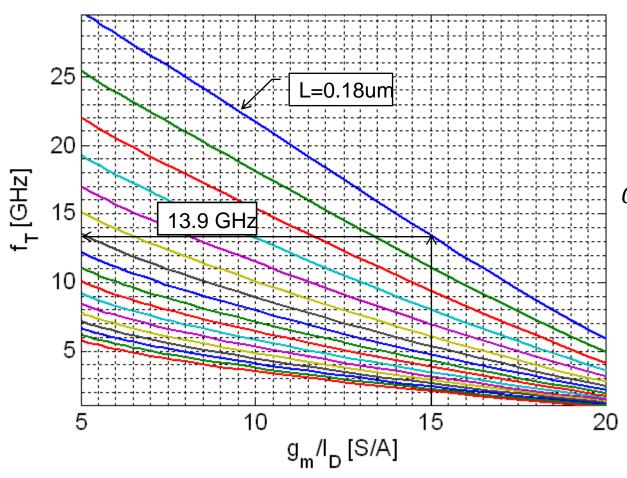


$$I_D = \frac{g_m}{\frac{g_m}{I_D}} = \frac{10mS}{15\frac{S}{A}} = 0.67mA$$

$$W = \frac{I_D}{\frac{I_D}{W}} = \frac{0.67mA}{11.8\frac{A}{m}} = 56.6\mu m$$

Determine C_{gg} via f_T Look-up

NMOS, 0.18...0.5um (step=20nm), V_{DS}=0.9V



$$C_{gg} = \frac{g_m}{\omega_T}$$

$$C_{gg} = \frac{10mS}{2\pi \cdot 13.9GHz} = 114fF$$

Matlab Script

```
% Basic sizing example
clear all;
close all;
% Load parameters
load 180nch.mat;
% Specification
qm = 10e-3;
% Chosen inversion levels and resulting drain current
gm id = [25 15 5]';
ID = qm./qm id
% Current density and width
JD = lookup(nch, 'ID W', 'GM ID', gm id)
W = ID./JD
% Transit frequency and Cgg
wT = lookup(nch, 'GM CGG', 'GM ID', gm id);
Cqq = qm./wT
```

Result

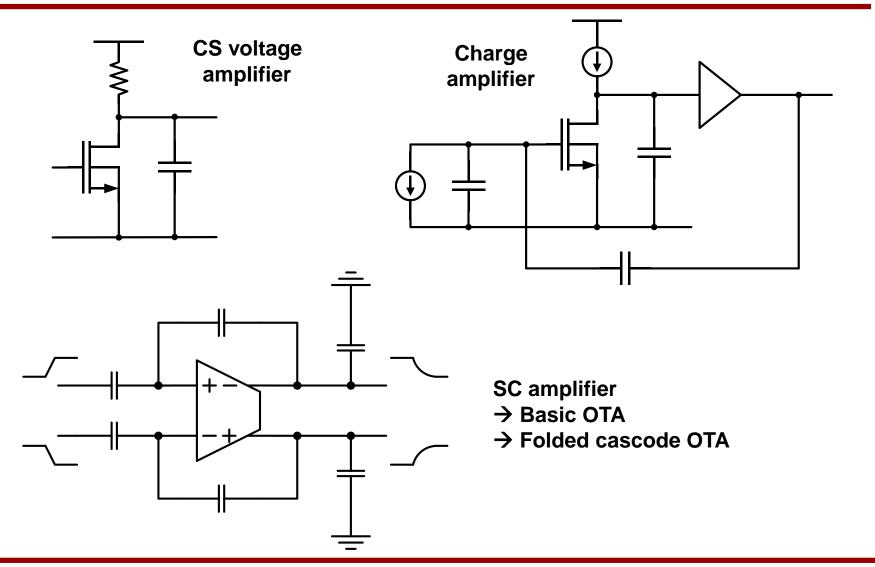
g _m /I _D [S/A]	25 (weak inversion)	15 (moderate inversion)	5 (strong inversion)
g _m [mS]	10	10	10
I_D [mA]	0.4	0.67	2
I _D /W [A/m]	0.12	11.8	83.3
W [μm]	3243	56.7	24.0
f _⊤ [GHz]	0.37	13.9	32.3
C _{gg} [fF]	4346	114	49

- Weak inversion
 - Small current, large device, large capacitance
- Strong inversion
 - Large current, small device, small capacitance
- Moderate inversion
 - A good compromise!

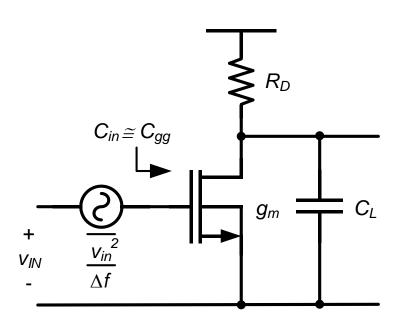
More Examples

- Noise-limited gain stages
 - CS voltage amplifier
 - Basic charge amplifier
 - Basic OTA for switched-capacitor circuits
 - Folded-cascode OTA for switched-capacitor circuits
- Distortion-limited gain stages
- Design with process corners

Noise-Limited Gain Stages — Overview



CS Voltage Amplifier



Input-referred noise

$$\frac{\overline{v_{in}^2}}{\Delta f} \cong 4kT\gamma_n \frac{1}{g_m}$$

Gain-bandwidth product

$$GBW = \frac{1}{2\pi} \frac{g_m}{C_L} = \frac{1}{2\pi} \frac{g_m}{FO \cdot C_{gg}} = \frac{f_T}{FO}$$

"Fan-out"

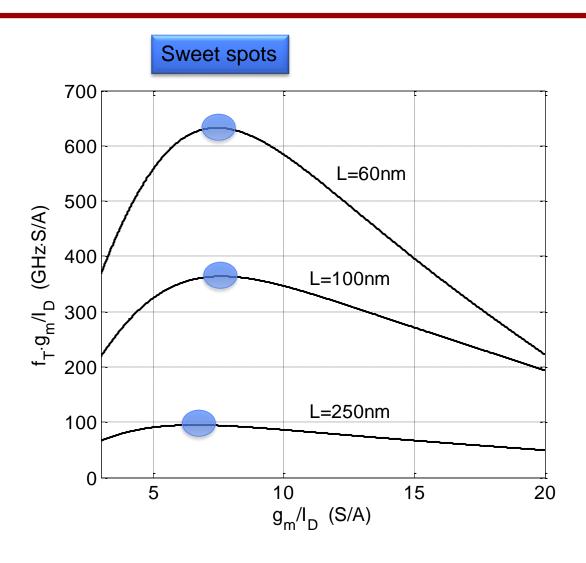
$$FO = \frac{C_L}{C_{in}} \cong \frac{C_L}{C_{gg}}$$

Efficiency

$$\frac{GBW}{I_D} = \frac{GBW}{g_m \cdot \frac{I_D}{g_m}} = \frac{\frac{f_T}{FO}}{\frac{4kT\gamma_n}{\overline{v_{in}}^2} \cdot \frac{I_D}{g_m}} \propto \frac{g_m}{I_D} \cdot f_T$$

- For a given noise level and fan-out, the efficiency of the circuit scales with the product of g_m/I_D and f_T
- This has been recognized and used in the design of RF low-noise amplifiers, see e.g.
 - Shameli, ISLPD 2006
 - Taris, RFIC 2011

Product of g_m/I_D and f_T

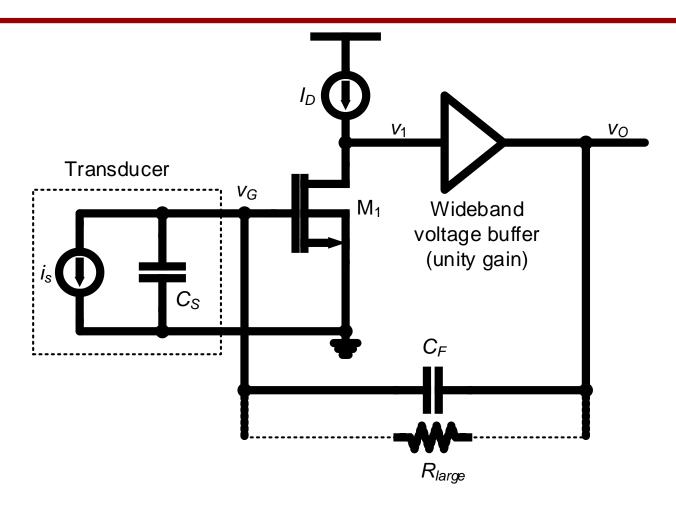


Sizing Example

```
% Constants and design parameters
kB = 1.38e-23;
T = nch.TEMP;
gamma_n = 1;
vin_noise = 1e-9;
L = 0.06;
% Set inversion level to sweet spot
gm_ID = 7;
% Compute gm based on noise specification
gm = 4*kB*T*gamma_n/vin_noise^2
% Compute drain current and device width
ID = gm/gm ID
JD = lookup(nch, 'ID_W', 'GM_ID', gm_ID, 'L', L);
W = ID/JD
```

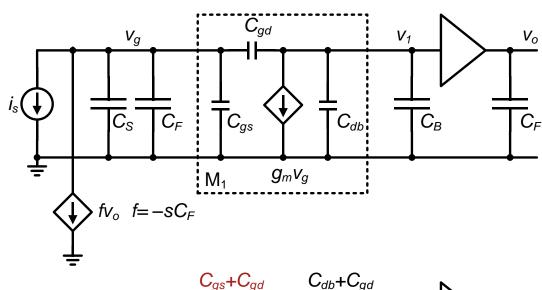
Results: $g_m = 16.6 \text{ mS}$ $I_D = 2.4 \text{ mA}$ $W = 28 \mu\text{m}$

Basic Charge Amplifier

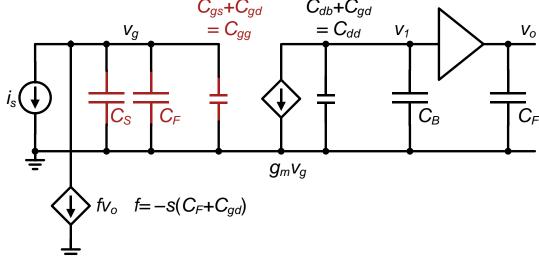


Used in photodetectors, MEMS interfaces, etc.

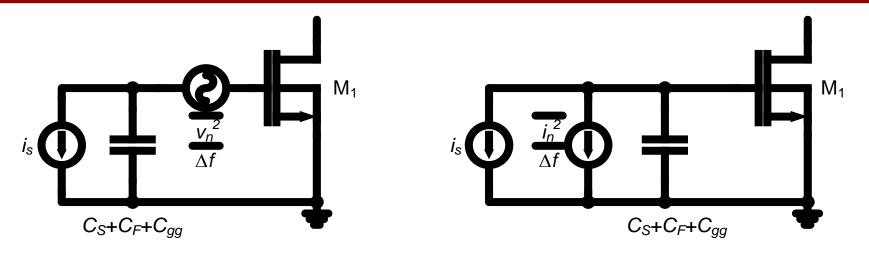
Two-Port Model (Shunt-Shunt)







Relevant Sub-Circuit for Noise Analysis



$$\frac{\overline{i_n^2}}{\Delta f} = \frac{\overline{v_n^2}}{\Delta f} \ \omega^2 (C_S + C_F + C_{gg})^2 = \frac{4kT\gamma_n}{g_m} \omega^2 (C_S + C_F + C_{gg})^2$$

- Transconductance (g_m) and gate capacitance (C_{gg}) are fundamentally linked $(C_{gg}, g_m \propto W)$
- There exists an optimum device size

Scenario 1: Optimization Assuming Constant ω_T

$$g_m = \omega_T C_{gg} \qquad \frac{\overline{i_n^2}}{\Delta f} = \frac{4kT\gamma_n}{\omega_T C_{gg}} \omega^2 (C_S + C_F + C_{gg})^2$$

The noise is minimized when the following term is minimized:

$$\frac{\left(C_{S} + C_{F} + C_{gg}\right)^{2}}{C_{gg}} \qquad \Rightarrow C_{gg,opt} = C_{S} + C_{F}$$

- This is a classical textbook result
 - See e.g. Chan Carusone, 2011

Scenario 2: Optimization Assuming Square Law & Constant I_D

$$g_{m} = \sqrt{2I_{D}\mu C_{ox} \frac{W}{L}} \cong \sqrt{3I_{D} \frac{\mu}{L^{2}} C_{gg}}$$

$$\frac{\overline{i_{n}^{2}}}{\Delta f} = \frac{4kT\gamma_{n}}{\sqrt{3I_{D} \frac{\mu}{L^{2}} C_{gg}}} \omega^{2} (C_{S} + C_{F} + C_{gg})^{2}$$

The noise is minimized when the following term is minimized:

$$\frac{\left(C_S + C_F + C_{gg}\right)^2}{\sqrt{C_{gg}}} \qquad \Rightarrow C_{gg,opt} = \frac{C_S + C_F}{3}$$

- This is another classical result
 - See e.g. Sansen, 1990

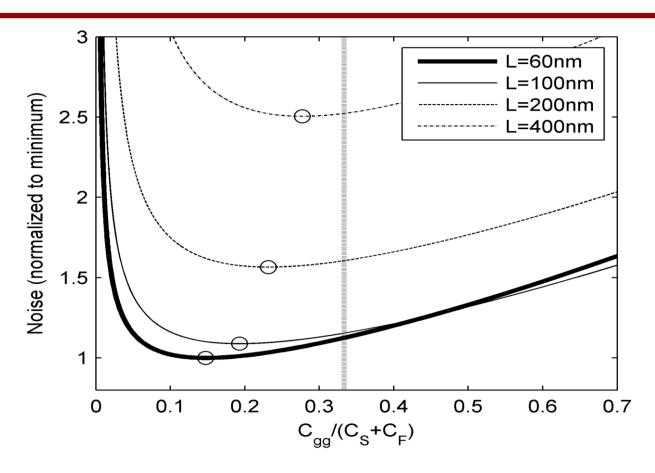
Issue & Solution

- The square does not apply to modern devices
- But, the optimum can be easily found using lookup table data

```
% Parameters
Cf_plus_Cs = 1e-12;
ID = 1e-3;
W = 5:1000;
L = [0.06 0.1 0.2 0.4];

% Compute relative noise level
Cgg = [W; W; W; W].*lookup(nch, 'CGG_W', 'ID_W', ID./W, 'L', L);
gm = [W; W; W; W].*lookup(nch, 'GM_W', 'ID_W', ID./W, 'L', L);
Noise = (Cf_plus_Cs + Cgg).^2./gm;
```

Result



 Optimum approaches square-law solution for long channels, but is far off for short channel

Scenario 3: Optimization Assuming Constant Noise and BW

- This is the scenario most frequently encountered in practice
- Analysis shows that

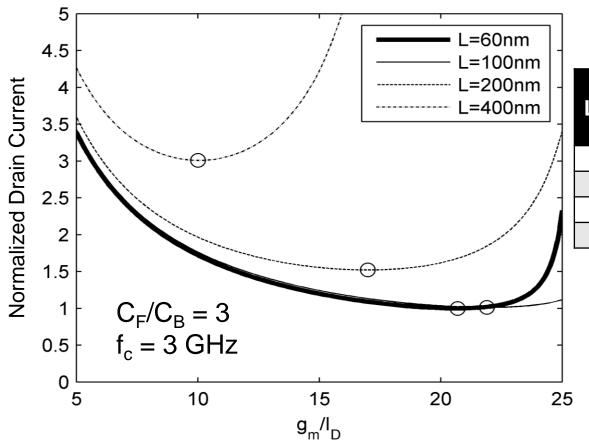
$$I_D \propto \left(\frac{1}{1 - \frac{C_B}{C_F} \frac{\omega_c}{\omega_T}}\right)^2 \cdot \frac{I_D}{g_m}$$
 $\omega_c \to \text{BW spec}$ $C_B \to \text{Buffer input capacitance}$

- Minimizing the current boils down to optimizing the tradeoff between g_m/I_D and ω_T
- First-order optimum assuming square law $(g_m/I_D \cdot \omega_T = const.)$

$$\omega_{T,opt} = 3 \frac{C_{\rm B}}{C_F} \omega_c$$
 $C_{gg} = \frac{C_S + C_F}{2}$

Example: Actual Optima Using Lookup Table Data

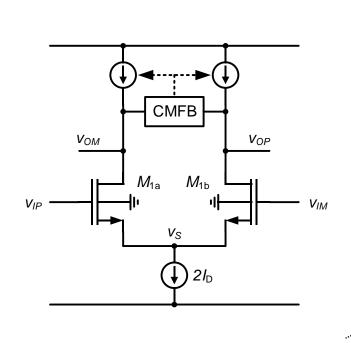
```
gm_ID = 5:0.1:25;
wT = lookup(nch, 'GM_CGG', 'GM_ID', gm_ID, 'L', L);
```



	Optimum Parameters			
L (nm)	g _m /I _D (S/A)	f _T (GHz)	$C_{gg}/(C_S+C_F)$	
60	20.7	9.6	0.116	
100	21.9	7.5	0.155	
200	17.0	5.1	0.247	
400	10.0	3.9	0.345	

Actual optima are far from square law prediction

Basic OTA for Switched Capacitor Circuit



(Switches not shown)

$$\beta = \frac{C_F}{C_F + C_S + C_{gs}}$$

$$C_{Ltot} = C_L + (1 - \beta)C_F$$

 $\overline{v_{od}^2} = 2 \frac{\gamma_n}{\beta} \frac{k_B T}{C_{Itot}}$

$$\beta_{max} = \frac{C_F}{C_F + C_S}$$

 C_F

 V_{od}

Optimization

- Design equations are similar to charge amplifier
 - Main difference is self-loading by feedback network
- Analysis shows

$$I_D \propto \left(\frac{1 + \frac{C_S}{C_F} - \frac{\omega_C}{\omega_{TS}}}{1 - \left(1 + \frac{C_L}{C_F}\right)\frac{\omega_C}{\omega_{TS}}}\right)^2 \frac{I_D}{g_m} \qquad \omega_{TS} = \frac{g_m}{C_{gS}}$$

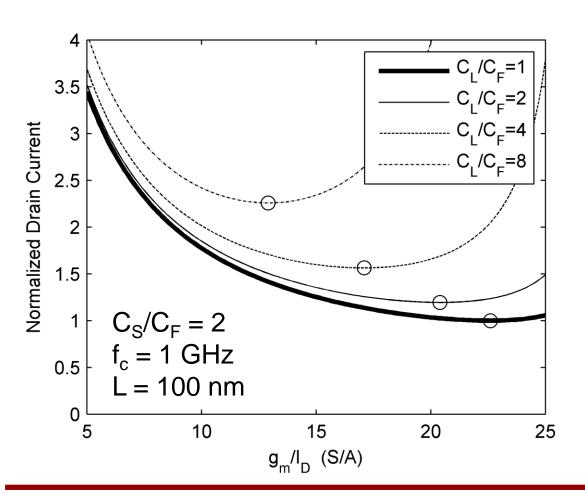
Optimum assuming square law

$$\omega_{Ts,opt} = 3\frac{C_L}{C_F}\omega_c + 3$$

$$C_{gs,opt} = \frac{C_S + C_F}{2}$$

Example: Actual Optima Using Lookup Table Data

gm_ID = 5:0.1:25; wTs = lookup(nch, 'GM_CGS', 'GM_ID', gm_ID, 'L', L);

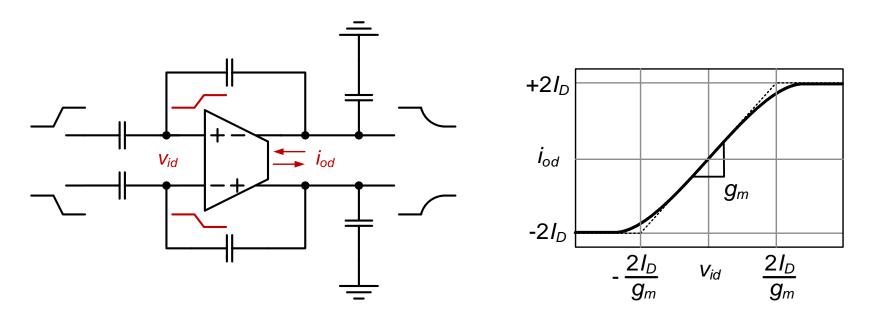


	Optim	Optimum Parameters			
C _L /C _F	g _m /I _D (S/A)	f _{Ts} (GH z)	β/β _{max}		
1	22.6	12.0	0.857		
2	20.4	15.6	0.825		
4	17.1	22.3	0.788		
8	12.9	35.6	0.755		

Optimum shifts to higher inversion levels for larger C_L

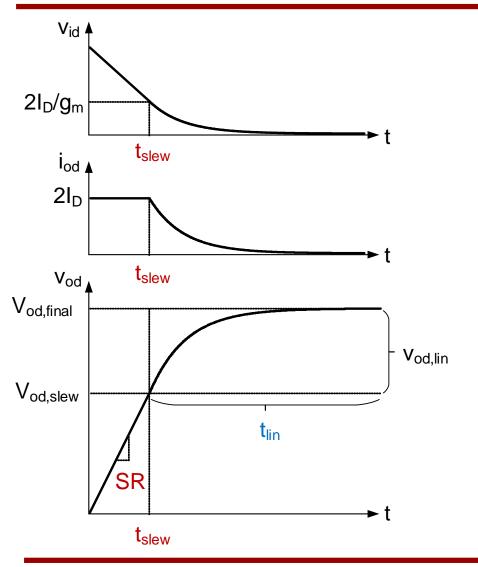
Slewing

- The preceding results all assumed small-signal operation
- In reality, switched capacitor circuits suffer from slewing



The input pair leaves its linear region during the initial transient

Settling Time



Linear Settling Time Constant

$$\tau = \frac{C_{Ltot}}{\beta g_m}$$

Slew Rate

$$SR = \frac{2I_D}{C_{Ltot}} = \frac{2I_D}{\tau \beta g_m}$$

Total Settling Time (ε_d = dynamic error)

$$t_s = t_{slew} + t_{lin} = \tau (X - 1 - ln(\varepsilon_d X))$$

$$X = \frac{v_{od,final}}{v_{od,lin}} = v_{od,final} \cdot \frac{\beta}{2} \frac{g_m}{I_D}$$

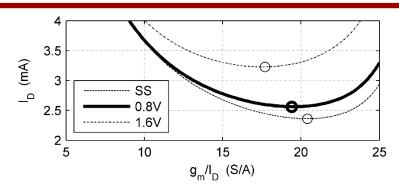
Optimization

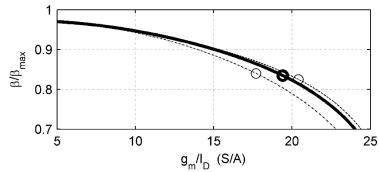
- There is no longer a closed form equation that can relate the design specs to the drain current
- But, we can still solve this problem using lookup tables!
- 1. Sweep g_m/I_D
- 2. For each g_m/I_D and for a range of β , compute the following:
 - a) C_{Ltot} based on noise specification
 - b) X, I_D, g_m
 - c) C_{gs} based on f_T and g_m
 - d) Actual β value
- 3. Now find the self-consistent values of β
- 4. Plot I_D versus g_m/I_D at the self-consistent points

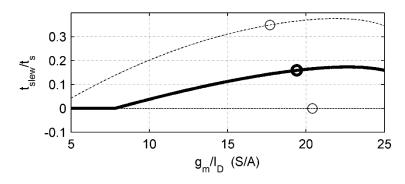
Sample Matlab Code

```
% Sweep range for gm/ID and beta
gm ID = 5:0.1:25;
beta_sweep = linspace(0.25*beta_max, beta_max, 1000);
wts = lookup(nch, 'GM_CGS', 'GM_ID', gm_ID, 'L', L);
for i = 1:length(vodfinal);
  for j = 1:length(gm_ID)
    % compute CLtot based on noise specification
    CLtot = 2*kB*T*gamma./beta_sweep/vod_noise^2;
    % compute ratio X = vodfinal/vodlin, current and component sizes
    X = vodfinal(i)*beta_sweep/2*gm_id(j); X(X<1) = 1;
    ID = CLtot./beta_sweep/gm_id(j)/ts.*(X-1 - log(ed*X));
    gm = gm_id(j)*ID; Cgs = gm/wts(j); CF = CLtot./(CL_CF + 1-beta_sweep);
    % compute actual beta and find self-consistent point
    beta_actual = CF./(CF*(1+CS_CF) + Cgs);
    d = beta_actual - beta_sweep;
    idx = find(d(1:end-1).*d(2:end)<0);
    if (idx) ID_valid(j,i) = ID(idx); end
  end
end
```

Example $(v_{od,final} = 10mV (SS), 0.8V, 1.6V)$







Parameters:

$$C_S/C_F = C_L/C_F = 2$$

 $t_s = 1.1 \text{ nS}$
 $L = 100 \text{ nm}$

- Optimum shifts to smaller g_m/I_D for larger signal ($v_{od,final}$)
- Optimum feedback factor stays close that of small-signal (SS) optimum
- Slewing time about 15...33%
 - Note: The 1.6V example is not practical; serves only illustrative purposes

Sizing

% Capacitance values

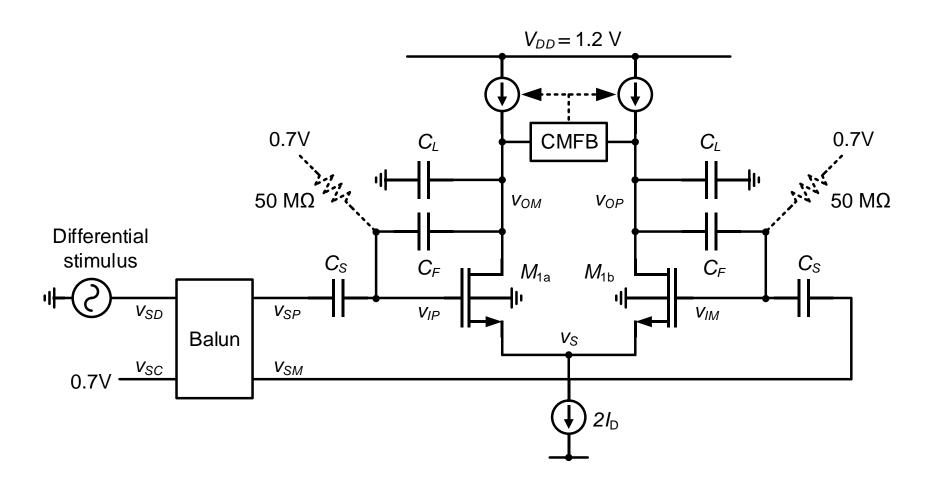
```
CLtot = 2*kB*T*gamma./beta_opt/vod_noise^2
CF = CLtot / (CL_CF + 1-beta_opt)
CS = CS_CF*CF
CL = CL_CF*CF
```

% Device size

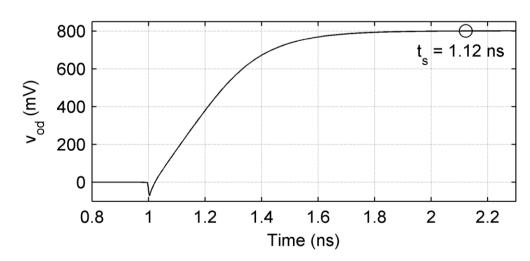
```
JD = lookup(nch, 'ID_W', 'GM_ID', gm_ID_opt, 'L', L)
W = ID_opt/JD
```

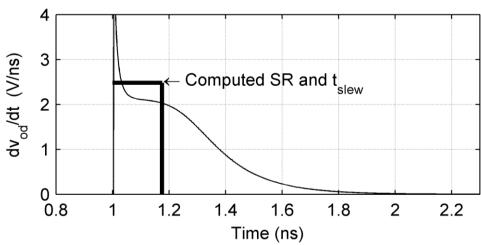
```
Results (for v_{od,final} = 0.8V): C_{Ltot} = 2.06 \text{ pF} C_{L} = 1.52 \text{ pF} C_{F} = 0.76 \text{ pF} C_{S} = 1.52 \text{ pF} I_{D} = 2.6 \text{ mA} W = 692 \text{ } \mu\text{m}
```

Spice Testbench



Simulation Result

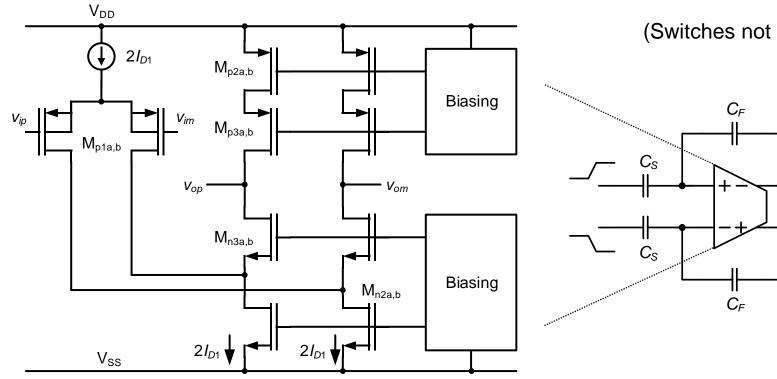




- Slew rate somewhat smaller than expected
 - Junction caps (neglected in design script)
 - Differential pair does not steer fully
- Linear portion somewhat faster than expected due to r_{ds} (neglected in design script)
- Final result is very close to target

Folded Cascode OTA for Switched **Capacitor Circuit**

(CMFB not shown)



(Switches not shown)

- Higher DC gain than basic OTA
- Nondominant pole (f_{p2}), reduced output swing

 V_{od}

Specifications

Parameter	Value	Comment
C _s /C _F	2	Closed-loop gain
C _L /C _F	1	Near optimum for pipeline ADC
Output swing	800 mV _{pp}	Differential
Total integrated output noise	400 μV_{rms} (DR = 57 dB)	Differential
Phase margin	75 °	For optimum transient settling
Dynamic settling error	0.1 %	
DC loop gain	> 50	Can use gain boosting if more gain is needed
Settling time	As small as possible (limited by f _{p2})	Ignore slewing (for simplicity)
Power dissipation	Minimize	

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Design Equations



$$\beta = \frac{C_F}{C_F + C_S + C_{in}}$$

$$\beta = \frac{C_F}{C_F + C_S + C_{in}} \qquad C_{in} \cong C_{ggp1} + C_{gdp1} \frac{g_{mp1}}{g_{mn3}}$$



Time Constant

$$\tau \cong \frac{C_{Ltot}}{\boldsymbol{\beta} \kappa g_m}$$

$$C_{Ltot} = C_L + (1 - \beta)C_F + C_{self}$$

Self loading (junction cap)

$$\kappa \cong \frac{g_{mn3}}{g_{mn3} + g_{dsp1} + g_{dsn2}}$$

Current divider at cascode

DC Loop Gain

$$RR_0 = \beta \kappa g_{mp1} R_o$$

$$\frac{1}{RR_0} \cong \frac{1}{\beta \kappa} \left(\frac{1}{\left(1 + \frac{g_{m2,3}}{g_{dsp2}}\right)} \frac{g_{m2,3}}{g_{dsp3}} + \frac{1}{\left(1 + \frac{g_{m2,3}}{3g_{dsn2}}\right)} \frac{g_{m2,3}}{g_{dsn2}} \right)$$

Noise

$$\overline{v_{od}^2} = \frac{\alpha}{\beta} \frac{k_B T}{C_{Ltot}}$$

$$\alpha = 2\gamma_n \left(1 + \frac{(g_m/I_D)_{p2}}{(g_m/I_D)_{p1}} + 2\frac{\gamma_p}{\gamma_n} \frac{(g_m/I_D)_{n2}}{(g_m/I_D)_{p1}} \right)$$

Design Equations

Nondominant Pole

$$\omega_{p2} \cong \frac{g_{mn3} + g_{mbn3}}{C_{ddp1} + C_{ssn3} + C_{ddn2}} \cong \frac{g_{mn3} + g_{mbn3}}{C_{ssn3} + 3C_{ddn3}}$$

- Equation set is complex and tangled up
- No hope to find a closed-form solution
- Approach
 - First identify hard constraints to simplify the problem
 - Next "untangle" the equations using numerical sweep
 - Very similar to previous example on slewing

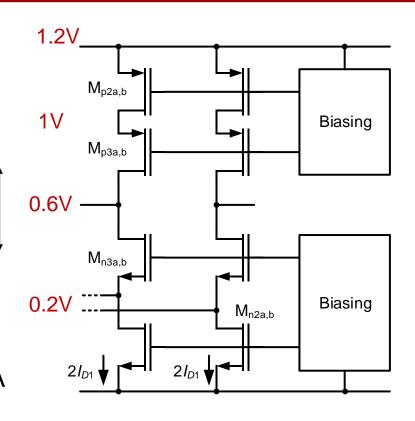
Swing Constraint

Swing ~± 400mV Differential

Decision:

$$\left(\frac{g_m}{I_D}\right)_{n2} = \left(\frac{g_m}{I_D}\right)_{n3} = \left(\frac{g_m}{I_D}\right)_{p2} = \left(\frac{g_m}{I_D}\right)_{p3} = 15 \text{ S/A}$$

$$\Rightarrow V_{Dsat} \cong \frac{2}{\underline{g_m}} = 133 mV$$



Gain Constraint

$$\frac{1}{RR_0} \cong \frac{1}{\beta \kappa} \left(\frac{1}{\left(1 + \frac{g_{m2,3}}{g_{dsp2}}\right)} \frac{g_{m2,3}}{g_{dsp3}} + \frac{1}{\left(1 + \frac{g_{m2,3}}{3g_{dsn2}}\right)} \frac{g_{m2,3}}{g_{dsn2}} \right)$$

gm_ID23 = 15;
% Conservative estimate for kappa
kappa_cons = 0.7;

% Reasonable estimate for beta

beta_max = 1/(1+CS_CF); beta_guess = 2/3*beta_max;



L = linspace(0.06, 1);

gm_gds_p2 = lookup(pch, 'GM_GDS', 'GM_ID', gm_ID23, 'VDS', 0.2, 'L', L); gm_gds_p3 = lookup(pch, 'GM_GDS', 'GM_ID', gm_ID23, 'VDS', 0.4, 'L', L); gm_gds_n3 = lookup(nch, 'GM_GDS', 'GM_ID', gm_ID23, 'VDS', 0.4, 'L', L); gm_gds_n2 = lookup(nch, 'GM_GDS', 'GM_ID', gm_ID23, 'VDS', 0.2, 'L', L);

Decision:

 $L_{n2,3} = 400 \text{ nm}$ $L_{p2,3} = 400 \text{ nm}$

Nondominant Pole & Settling Time Estimates

```
% Chosen lengths
Ln23 = 0.4; Lp23 = 0.4;
% Resulting device parameters
gmb gm n3 = lookup(nch, 'GMB GM', 'GM ID', 15, 'VDS', 0.4, 'L', Ln23);
gm_css_n3 = lookup(nch, 'GM_CSS', 'GM_ID', 15, 'VDS', 0.4, 'L', Ln23);
cdd_css_n3 = lookup(nch, 'CDD_CSS', 'GM_ID', 15, 'VDS', 0.4, 'L', Ln23);
% Nondominant pole
wp2 = 1/2/pi * gm_css_n3 * (1+gmb_gm_n3)/(1 + 3*cdd_css_n3)
% Set gain-bandwidth product for proper phase margin
fc = fp2/4
                                                                       Results:
% Settling time estimate
                                                                   f_{p2} = 1.74 \text{ GHz}
tau = 1/2/pi/fc
                                                                    f_c = 435 \text{ MHz}
epsilon_d = 1e-3;
ts = -tau*log(epsilon_d)
                                                                      t_{s} = 2.5 \text{ ns}
```

Sweep for Current Optimization

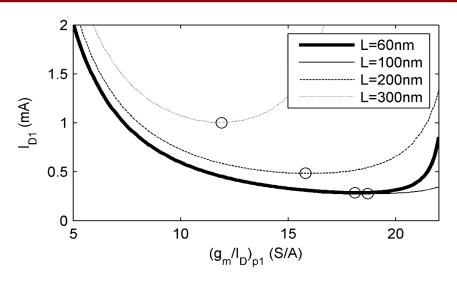
- 1. Sweep g_m/I_D of the input pair
- 2. For each g_m/I_D and for a range of β , compute
 - a) Excess noise factor α
 - b) C_{I tot} based on noise specification*
 - c) Factor κ
 - d) Input pair transconductance
 - e) C_{in} , C_f , and actual value of β
- 3. Find the self-consistent values of β
- 4. Plot I_D versus g_m/I_D for the self consistent points

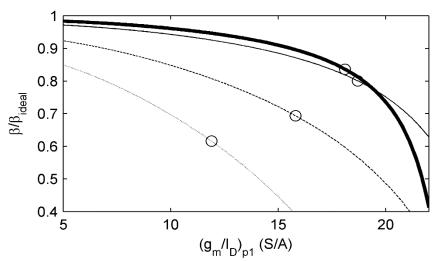
*Caveat: We do not know C_{self} (part of C_{Ltot}) at this point; start by assuming $C_{self} = 0$ and refine later

Matlab Script

```
% Sweep parameters
Cself_est = 0;
Lp1 = [0.06 \ 0.1 \ 0.2 \ 0.3]; gm \ ID1 = 5:0.1:22;
beta sweep = linspace(0.25*beta max, beta max, 200);
for i = 1:length(Lp1)
  % Compute input pair device parameters for each length
  wt1 = lookup(pch, 'GM CGG', 'GM ID', gm ID1, 'L', Lp1(i));
  gm_gds1 = lookup(pch, 'GM_GDS', 'GM_ID', gm_ID1, 'L', Lp1(i));
  Cgd_Cgg1 = lookup(pch, 'CGD_CGG', 'GM_ID', gm_ID1, 'L', Lp1(i));
  for i = 1:length(gm ID1)
    % Compute excess noise factor and total load to meet the noise spec
    alpha =2*gamma_n*(1+gm_id23/gm_ID1(j)+2*gamma_p/gamma_n*gm_id23/gm_ID1(j));
    CLtot = alpha./beta sweep*kBoltzmann*nch.TEMP/vod noise^2;
    % Compute required gm to meet the gain-bandwidth requirement
    kappa = 1/(1 + 1/gm_gds1(j)*gm_ID1(j)/gm_id23 + 2/gm_gds_n3);
    gm1 = 2*pi*fc*CLtot./beta sweep/kappa;
    % Compute the amplifier's input capacitance and resulting beta
    Cin = gm1/wt1(j)*(1 + Cgd_Cgg1(j)*gm_ID1(j)/gm_id23); CF = (CLtot - Cself_est)./(CL_CF+1-beta_sweep);
    beta actual = CF./(CF+CS CF*CF+Cin);
    % Find self-consistent beta values and store parameters
    d = beta \ actual - beta \ sweep; \ idx = find(d(1:end-1).*d(2:end)<0);
    if(idx) ID1_valid(i,j) = gm1(idx) / gm_ID1(j); end
  end
end
```

Result





- Decide to use L =100 nm
- $I_D = 276 \mu A, g_m/I_D = 18.7 S/A$
- Can now size all devices and estimate C_{self}

Sizing and C_{self} Estimate

```
% Sizing
Wp1 = ID1_chosen/lookup(pch, 'ID_W', 'GM_ID', gm_id1_chosen, 'L', Lp1)
Wp2 = ID1_chosen/lookup(pch, 'ID_W', 'GM_ID', gm_id23, 'VDS', 0.2, 'L', Lp23)
Wp3 = ID1_chosen/lookup(pch, 'ID_W', 'GM_ID', gm_id23, 'VDS', 0.4, 'L', Lp23)
Wn2 = 2*id1_chosen/lookup(nch, 'ID_W', 'GM_ID', gm_id23, 'VDS', 0.2, 'L', Ln23)
```

Wn3 = ID1 chosen/lookup(nch, 'ID W', 'GM ID', gm id23, 'VDS', 0.4, 'L', Ln23)

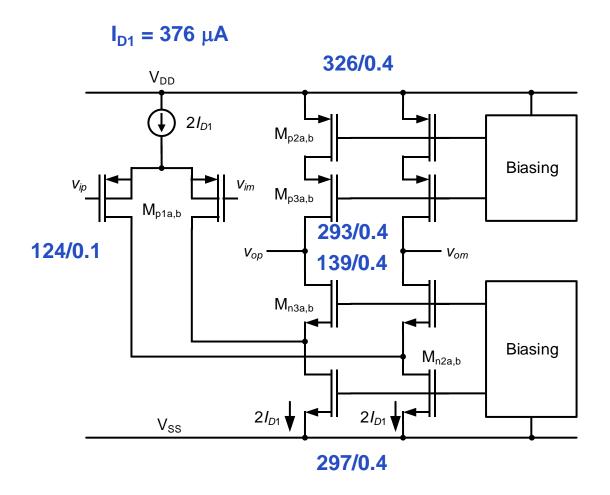
% Estimate Cself

```
Cddp3 = Wp3*lookup(pch, 'CDD_W', 'GM_ID',gm_id23, 'VDS',0.4, 'VSB',0.2, 'L', Lp23) Cddn3 = Wn3*lookup(nch, 'CDD_W', 'GM_ID',gm_id23, 'VDS',0.4, 'VSB',0.2, 'L', Ln23) Cself actual = Cddp3 + Cddn3
```

- C_{self} turns out to be 208 fF, about 45% of C_{Ltot} → Significant!
- Run the script again with C_{self,est} = 208 fF
 - And repeat if desired, until "convergence"...

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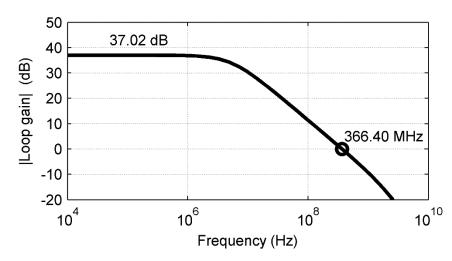
Final Design

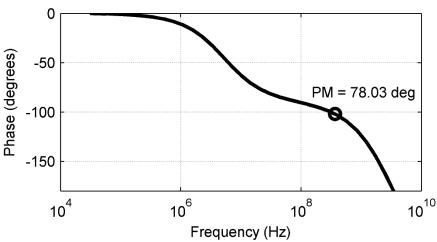


 $C_S = 370 \text{ fF}$ $C_F = 185 \text{ fF}$ $C_L = 182 \text{ fF}$

 $C_{self} = 283 fF$

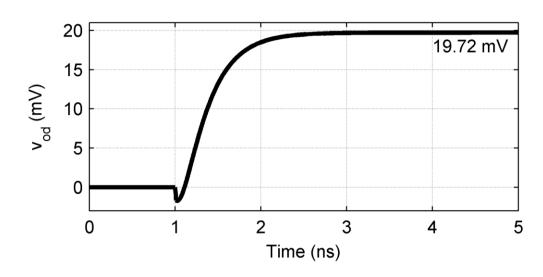
Loop Gain Simulation

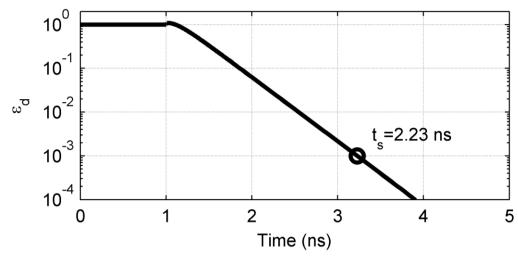




- Unity gain frequency smaller than targeted (435 MHz)
 - Remaining discrepancy in C_{self}
 - Impact of f_{p2}
- DC loop gain slightly larger than targeted (34 dB) due to conservative estimate
- Phase margin slightly larger than targeted due to reduced unity gain frequency

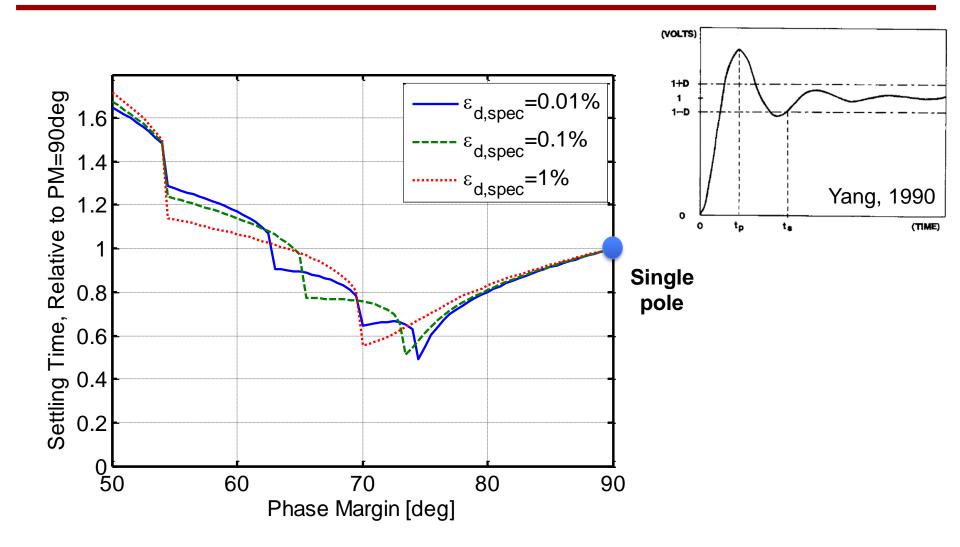
Transient Simulation



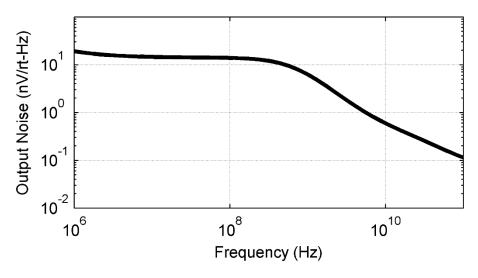


- Settling time is better than targeted (2.5 ns)
 - Due to non-dominant pole, which speeds up the transient
- Design meets settling requirements

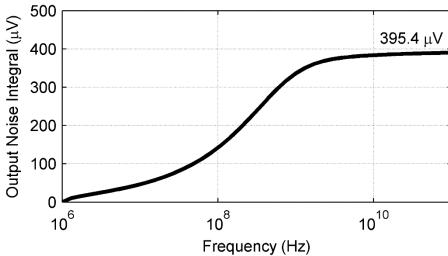
Settling Time as a Function of Phase Margin



Noise Simulation



Almost exactly on target



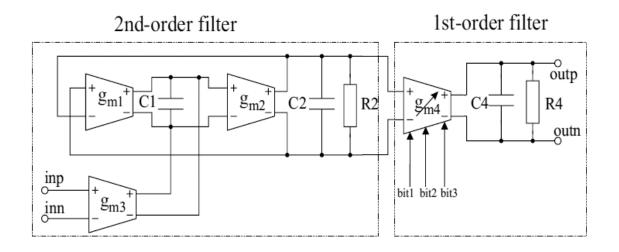
Possible Next Steps

- Errors are mostly due to first-order nature of design equations,
 which must omit second order effects to be useful
 - This is why we still run simulations...
- Design is very close to final specs and minor tweaking will get us very quickly to the final design point
- Next steps to consider
 - Try an n-channel input pair → simple change in code!
 - Revisit some of the initial design choices (e.g. channel lengths in output branch)
 - Include the effect of slewing if needed → small change in code!
 - Account for process variations → more later...

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Distortion-Limited Gain Stages

- Several types of circuit are limited by nonlinearities
 - RF LNAs, g_m-C filters, etc.



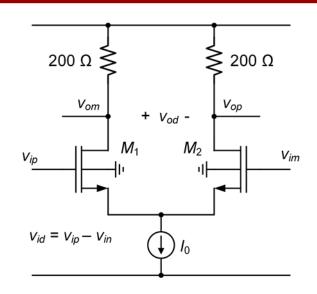
- It is possible to compute distortion based on g_m/I_D (for all inversion levels)
 - See Jespers & Murmann, ISCAS 2015

Example: Differential Amplifier

$$HD_3 = \frac{1}{24} \left(\frac{1}{nU_T}\right)^2 \frac{(1+3q)}{2(1+2q)^3} v_{id,pk}^2$$

$$q = \frac{1}{nU_T \cdot \frac{g_m}{I_D}} - 1$$

Valid for all inversion levels!



Parameter	Values			
v _{id,pk} (mV), Spec	10	40	10	40
HD ₃ (dB), Spec	-60.0	-60.0	-70.0	-70.0
g_{m}/I_{D} (S/A)	24.2	8.0	15.8	4.7
I _{TAIL} (mA), SPICE	0.826	2.51	1.26	4.25
W (μm), SPICE	321	25.7	82.7	18.1
HD ₃ (dB), SPICE	- 61.0	-60.4	-70.6	-67.5

Design with Process Corners

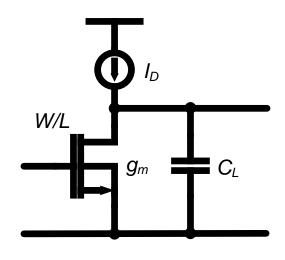
- Making circuits work across corners takes a significant amount of time (often dominates design time)
- No "magic bullet" that can cut this overhead to zero
 - But the g_m/I_D framework can help you think about corner behavior systematically

$$\begin{cases} \frac{g_{m}}{I_{D}} \end{cases} \quad \text{transconductance efficiency} \\ \begin{cases} \frac{I_{D}}{W} \end{cases} \quad \text{drain current density} \\ \begin{cases} \frac{g_{m}}{g_{ds}} \end{cases} \quad \text{intrinsic gain} \\ \begin{cases} \frac{g_{m}}{C} \end{cases} \quad \text{transit frequency}$$

How do these parameters vary across corners?

Example: Intrinsic Gain Stage

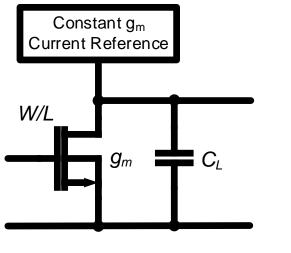
Biasing Scenario 1: Constant I_D



$$\frac{I_D}{W} = const.$$
 $GBW = \frac{g_m}{C_L} \neq const.$

- Moderate variations in V_{Dsat}
- Large variations in GBW

Biasing Scenario 2: Constant g_m

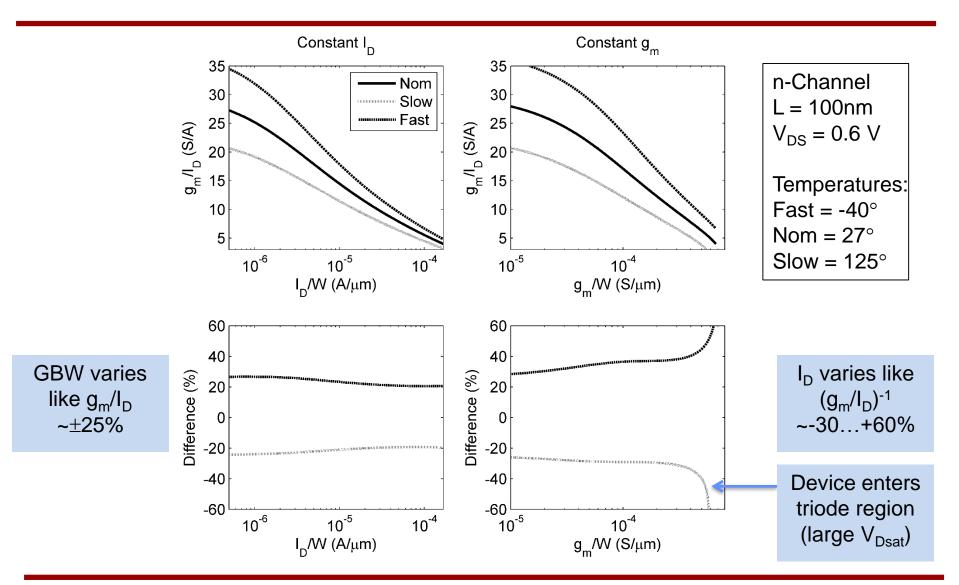


$$\frac{g_m}{W} = const.$$
 $GBW = \frac{g_m}{C_L} \approx const.$

- + Small variations in GBW
- Large variations in I_D and V_{Dsat}

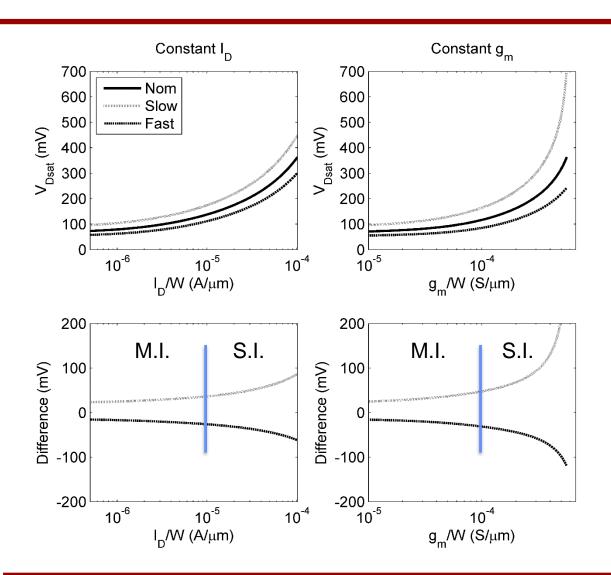
Practical designs often operate between these two extremes

g_m/I_D Across Corners



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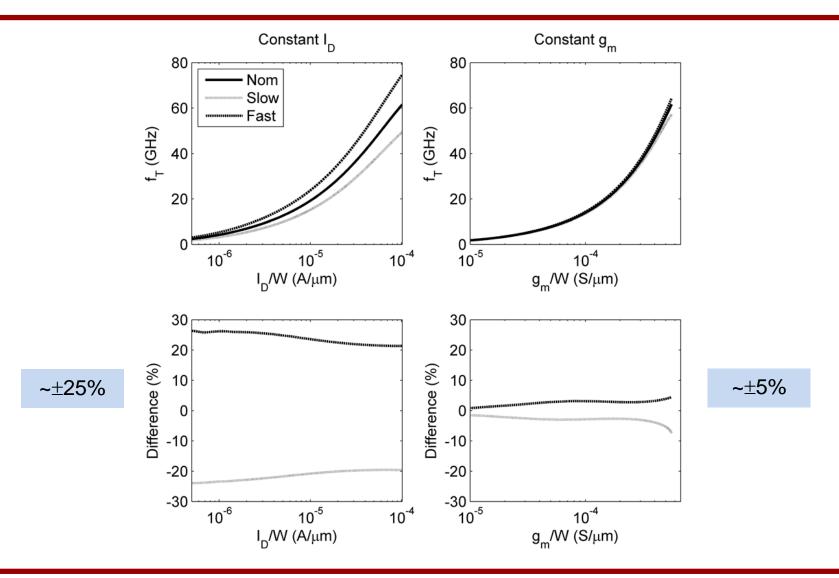
$V_{Dsat} = 2/(g_m/I_D)$ Across Corners



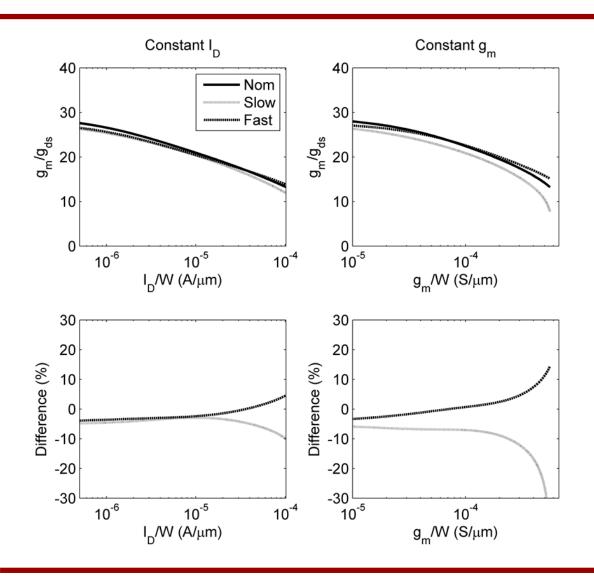
Strong Inversion (S.I.): Constant g_m biasing impractical (for low V_{DD})

Moderate Inversion (S.I.): Constant g_m biasing OK!

f_T Across Corners



g_m/g_{ds} Across Corners



Significant variations only in strong inversion (related to V_{Dsat} margin)

Design Flow

- Select a biasing scheme that matches your objectives
 - Constant I_D, constant g_m or something in-between
- Constant g_m design
 - Worry mostly about headroom, V_{Dsat} management (especially in strong inversion)
- Constant I_D design
 - Headroom management is typically less critical
 - Worry mostly about g_m and f_T variations ($\sim \pm 25\%$)
 - How to deal with these?

Two Options for Constant I_D Design Flow

- 1. Identify the "worst corner"
 - See e.g. Konishi et al., 2011
 - Design using lookup tables that represent the worst case
 - Typically slow+hot in class-A circuits (beware of exceptions!)
- 2. Pre-distort the design specifications
 - Knowing that we will lose 25% GBW in the worst corner, overdesign BW by 25% using nominal lookup table data

Required for both options: Design validation across all corners in Spice → No free lunch…

Example: Charge Amplifier Design

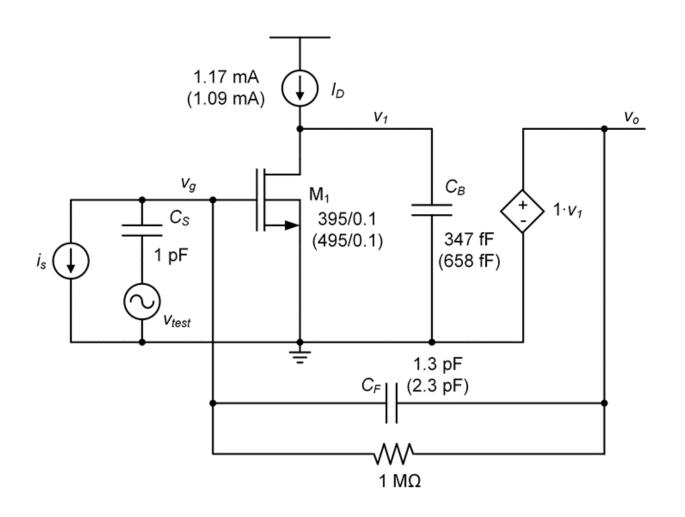
• Specs: GBW = 3GHz, Noise @ 3GHz = 50 fA/rt-Hz, $C_s = 1pF$

 To meet the GBW and noise spec in the slow/hot corner, overdesign GBW by ~1/0.7 = 1.4

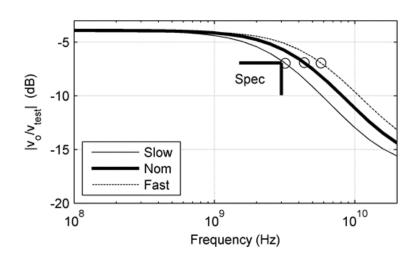
GBW target is 4.2 GHz

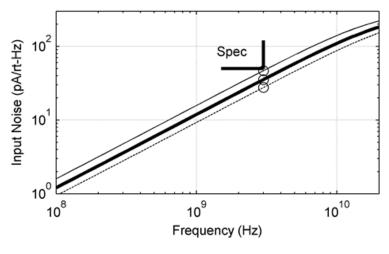
Now find optimum sizing of device as discussed earlier...

Schematic



Spice Results





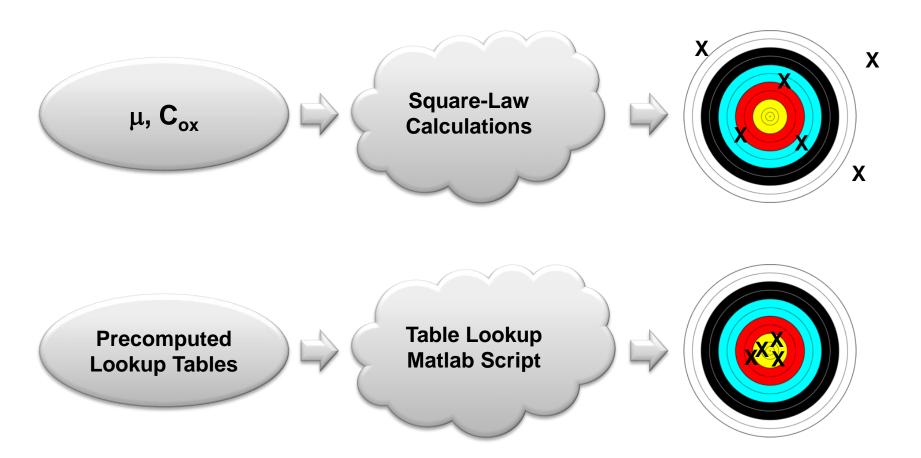
	Slow	Nom	Fast
f _c (GHz)	3.19	4.37	5.74
Deviation (%)	-27	0	+31
Noise at 3 GHz (pA/rt-Hz)	46.8	35.4	27.7
Deviation (%)	+32	0	-21

Summary

- Think $g_m/I_D!$
 - Weak inversion > 20 S/A → low power design
 - Moderate inversion 10...20 S/A → offers a nice compromise
 - Strong inversion < 10 S/A → high-speed design
- g_m/I_D shows up naturally in many circuit calculations and provides a link between important small- and large-signal parameters
- g_m/I_D-based design using pre-computed look-tables enables
 - Systematic circuit optimization using sweeps that are hard (or impossible) to perform in Spice
 - Efficient technology node porting via script re-use
 - Sanity checking of Spice results
 - All Matlab parameters match Spice simulation closely
 - Different from square law calculations using μC_{ox}, V_{GS}-V_t, which have little to no significance in Spice

Comparison

Spice results



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References

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